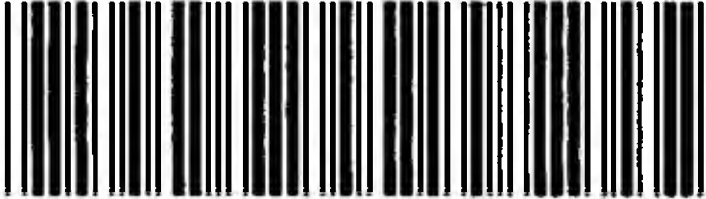


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,871	LEE, YUAN-CHUNG	
	Examiner	Art Unit	
	M. Lee	2622	

SEARCHED			
Class	Subclass	Date	Examiner
348	441, 452, 451, 448, 459, 699,	5/18/2007	ML
	700, 581,		
	554, 555		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference search history printout		5/18/2007	ML

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	5/18/2007	ML